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Standards

Irish Standard
I.S. EN 62228-2:2017

Integrated circuits - EMC evaluation of transceivers - Part 2: LIN transceivers

I.S. EN 62228-2:2017

Incorporating amendments/corrigenda/National Annexes issued since publication:

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National Foreword

I.S. EN 62228-2:2017 is the adopted Irish version of the European Document EN 62228-2:2017, Integrated circuits - EMC evaluation of transceivers - Part 2: LIN transceivers

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EUROPEAN STANDARD

EN 62228-2

NORME EUROPÉENNE

EUROPÄISCHE NORM

February 2017

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English Version

**Integrated circuits - EMC evaluation of transceivers -
Part 2: LIN transceivers
(IEC 62228-2:2016)**

Circuits intégrés - Évaluation de la CEM des émetteurs-
récepteurs - Partie 2: Émetteurs-récepteurs LIN
(IEC 62228-2:2016)

Integrierte Schaltungen - Bewertung der
elektromagnetischen Verträglichkeit von Sende-
Empfangsgeräten - Teil 2: LIN-Sende-Empfangsgeräte
(IEC 62228-2:2016)

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Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

EN 62228-2:2017

European foreword

The text of document 47A/994/FDIS, future edition 1 of IEC 62228-2, prepared by SC 47A "Integrated circuits" of IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62228-2:2017.

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- latest date by which the document has to be (dop) 2017-09-23
implemented at national level by
publication of an identical national
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Annex ZA (normative)

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NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 61967-1	-	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz - Part 1: General conditions and definitions	EN 61967-1	-
IEC 61967-4	-	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz - Part 4: Measurement of conducted emissions - 1 ohm/150 ohm direct coupling method	EN 61967-4	-
IEC 62132-1	-	Integrated circuits - Measurement of electromagnetic immunity - Part 1: General conditions and definitions	EN 62132-1	-
IEC 62132-4	-	Integrated circuits - Measurement of electromagnetic immunity, 150 kHz to 1 GHz - Part 4: Direct RF power injection method	EN 62132-4	-
IEC 62215-3	-	Integrated circuits - Measurement of impulse immunity - Part 3: Non-synchronous transient injection method	EN 62215-3	-
ISO 7637-2	-	Road vehicles - Electrical disturbances from conduction and coupling - Part-2: Electrical transient conduction along supply lines only	-	-
ISO 10605	-	Road vehicles - Test methods for electrical - disturbances from electrostatic discharge	-	-
ISO 17987-6	-	Road vehicles - Local Interconnect Network (LIN) - Part 6: Protocol conformance test specification	-	-

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INTERNATIONAL STANDARD

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**Integrated circuits – EMC evaluation of transceivers –
Part 2: LIN transceivers**

**Circuits intégrés – Évaluation de la CEM des émetteurs-récepteurs –
Partie 2: Émetteurs-récepteurs LIN**



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INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Integrated circuits – EMC evaluation of transceivers –
Part 2: LIN transceivers**

**Circuits intégrés – Évaluation de la CEM des émetteurs-récepteurs –
Partie 2: Émetteurs-récepteurs LIN**

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INTEGRATED CIRCUITS – EMC EVALUATION OF TRANSCEIVERS –

Part 2: LIN transceivers

FOREWORD

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International Standard IEC 62228-2 has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47A/994/FDIS	47A/998/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62228 series, published under the general title *Integrated circuits – EMC evaluation of transceivers*, can be found on the IEC website.

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INTEGRATED CIRCUITS – EMC EVALUATION OF TRANSCEIVERS –

Part 2: LIN transceivers

1 Scope

This part of IEC 62228 specifies test and measurement methods for EMC evaluation of LIN transceiver ICs under network condition. It defines test configurations, test conditions, test signals, failure criteria, test procedures, test setups and test boards. It is applicable for standard LIN transceiver ICs and ICs with embedded LIN transceiver and covers

- the emission of RF disturbances,
- the immunity against RF disturbances,
- the immunity against impulses and
- the immunity against electrostatic discharges (ESD).

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 61967-1, *Integrated circuits – Measurement of electromagnetic emissions 150 kHz to 1 GHz – Part 1: General conditions and definitions*

IEC 61967-4, *Integrated circuits – Measurement of electromagnetic emissions 150 kHz to 1 GHz – Part 4: Measurement of conducted emissions – 1 Ω /150 Ω direct coupling method*

IEC 62132-1, *Integrated circuits – Measurement of electromagnetic immunity – Part 1: General conditions and definitions*

IEC 62132-4, *Integrated circuits – Measurement of electromagnetic immunity 150 kHz to 1 GHz – Part 4: Direct RF power injection method*

IEC 62215-3, *Integrated circuits – Measurement of impulse immunity – Part 3: Non-synchronous transient injection method*

ISO 7637-2, *Road vehicles — Electrical disturbances from conduction and coupling – Part 2: Electrical transient conduction along supply lines only*

ISO 10605, *Road vehicles – Test methods for electrical disturbances from electrostatic discharge*

ISO 17987-6.2¹, *Road vehicles – Local interconnect network (LIN) – Part 6: Protocol conformance test specification*

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